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(71) Applicant (for all designated States except US): **KONINKLIJKE PHILIPS ELECTRONICS, N.V.** [NL/NL];
Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).

(72) Inventor; and

(75) Inventor/Applicant (for US only): **AMATO, Joseph M.**
[US/US]; 1109 McKay Drive, M/S-SJ41, San Jose, CA
95131-1706 (US).

(74) Common Representative: **KONINKLIJKE PHILIPS ELECTRONICS, N.V.**; c/o Shannon Lester, 1109 McKay
Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).

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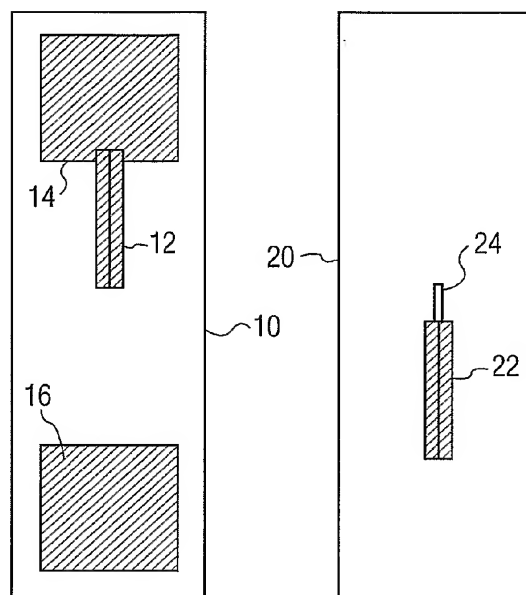
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— as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ,

[Continued on next page]

(54) Title: PROPORTIONAL VARIABLE RESISTOR STRUCTURES TO ELECTRICALLY MEASURE MASK MISALIGNMENT



(57) Abstract: A system, method and structures employing proportional variable resistors suitable for electrically measuring unidirectional misalignment of stitched masks in etched interconnect layers. In an example embodiment, there is a structure (10, 20) that comprises at least one proportional variable resistor (24) suitable for electrically measuring unidirectional misalignment of stitched masks in etched interconnect layers. The structure (10,20) comprises at least a first mask (10) and a second mask (20) that when superimposed comprise at least two test pads (14, 16) and interconnects (12, 22) the resistance between (24) which can be measured.

WO 2005/019938 A1



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